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(54) DEVICE AND METHOD FOR FINE ARRANGEMENT OF EXAMINATION SAMPLE

(57) Abstract:

PURPOSE: A fine arrangement device for samples to examine and a method thereof are provided to examine a plurality of samples by a single silde for minimizing the time and cost required for the sample testing and improve the worksbillty by minimizing the sampling time since the sampling is simply carried out manually by inserting blocks into insertion holes of a storage block once. CONSTITUTION: A fine arrangement device for samples to examine includes a sample storage part(100) mounted with at least one or more storage cassettes(103A) for forming a parafilh block(110A) by integrally soliditying a sample (105) with paraffin(100), a block storage part(300) having a plurality of sample insertion holes(310) integrally mounted to a storage cassette(103B) form inserting sample blocks(211) formed by the integration solidification of the sample and the paraffin, and a punching element(200) for sampling the sample blocks from the paraffin block to form the sample insertion holes to be inserted by the sample blocks.

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